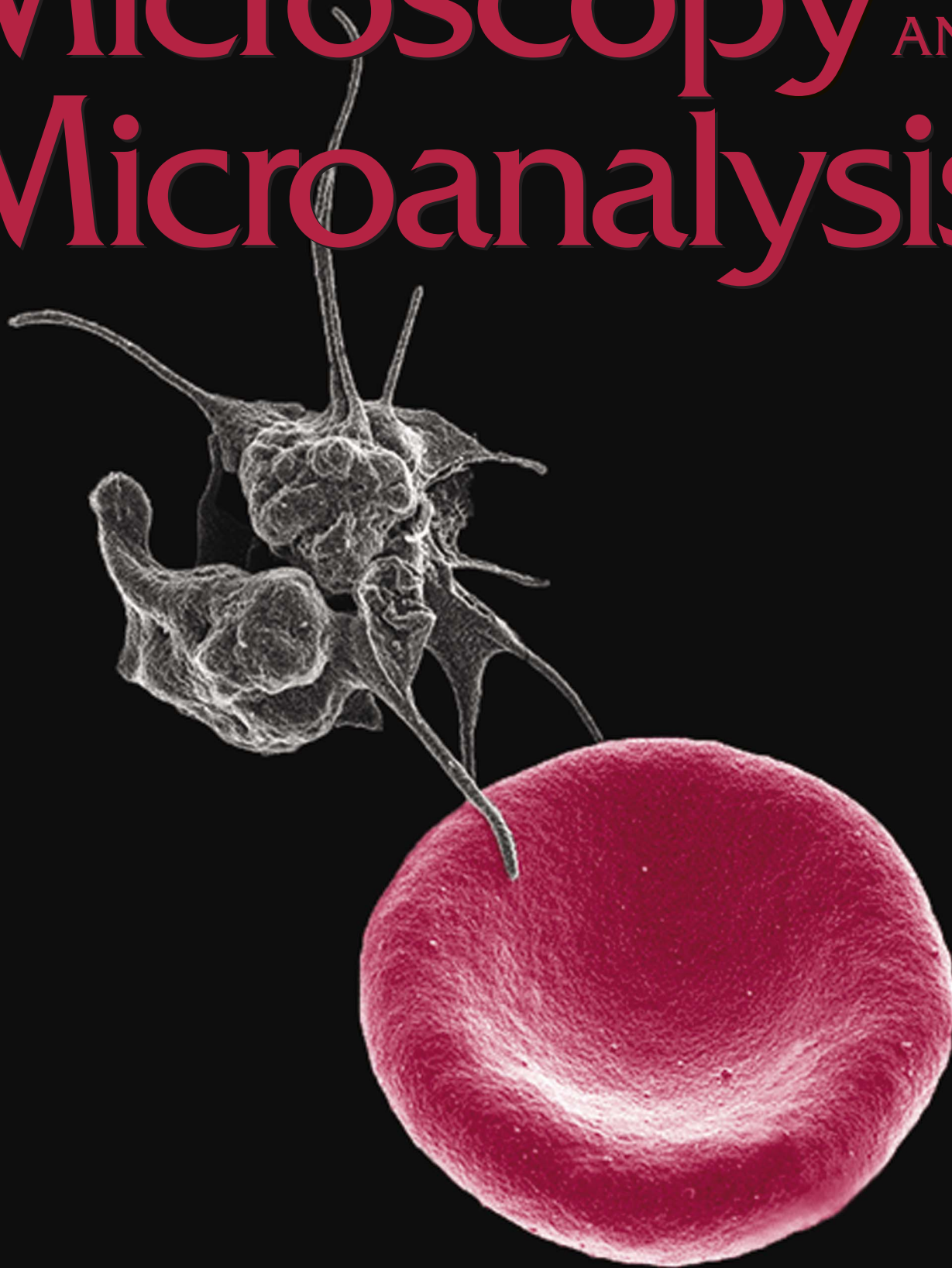


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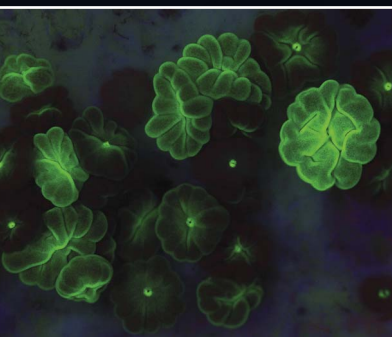
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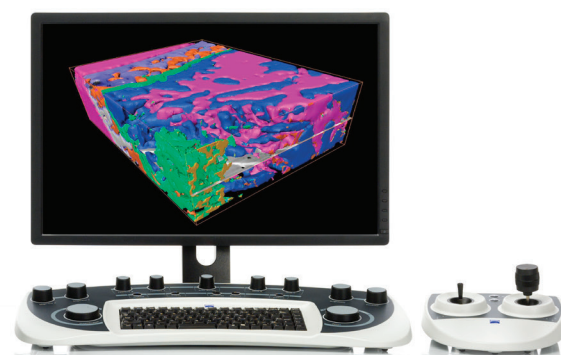
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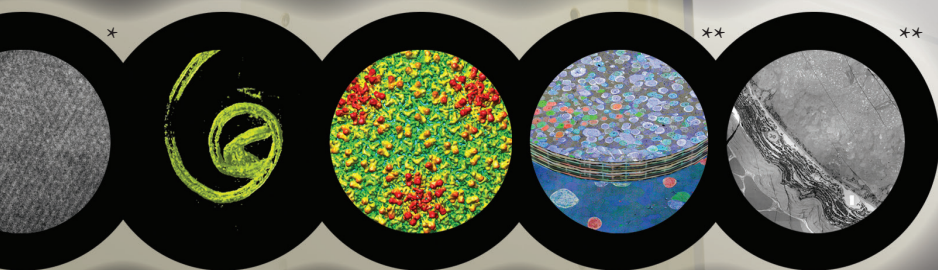
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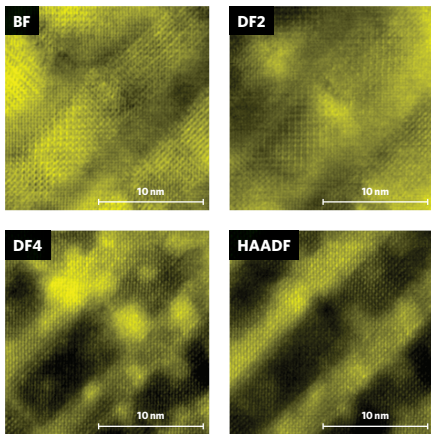


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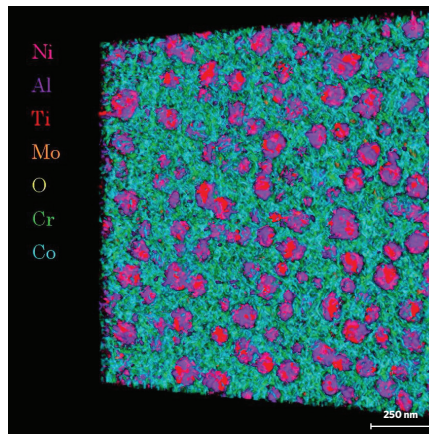


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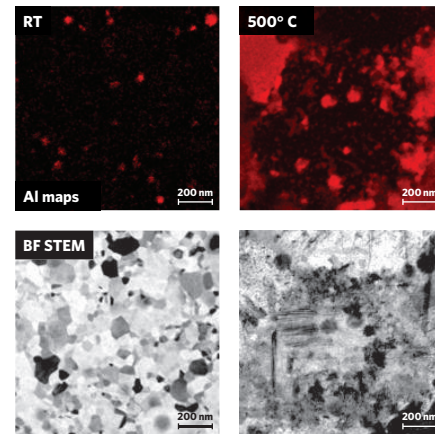
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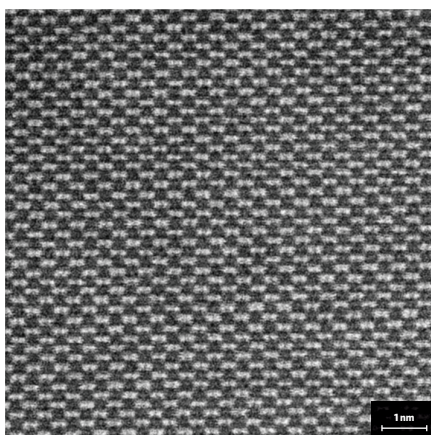
4 channel simultaneous HRSTEM imaging of SrTiO₃ using 4 STEM detectors.



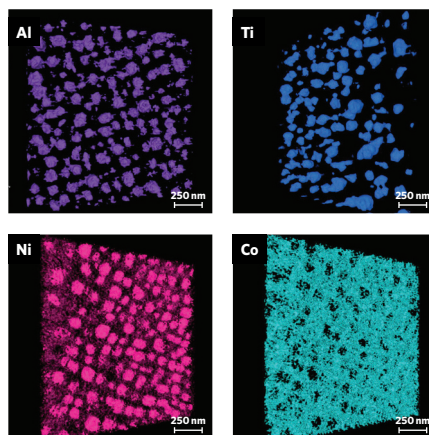
Combined 3D EDS map: Ni, Al, Ti, Mo, Cr, and Co.



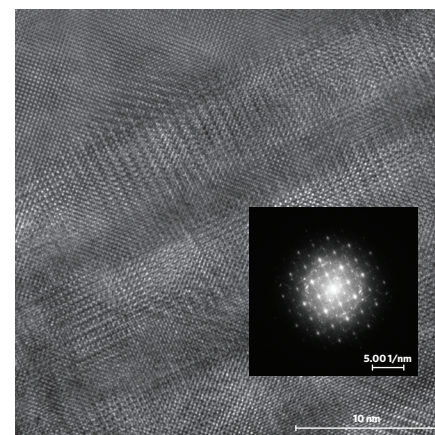
Temperature driven Al aggregation in solar cell. Sample courtesy of Dr. S. Kraschewski, U. Erlangen.



HRSTEM of Si (110) at 200kV.



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HRTEM image of SrTiO₃ with Ceta 16M camera.

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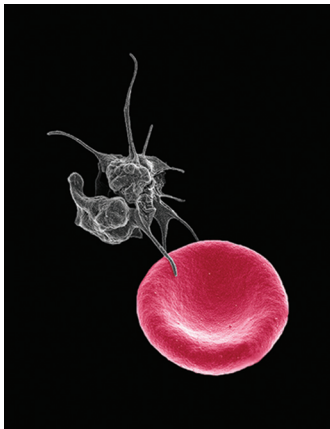
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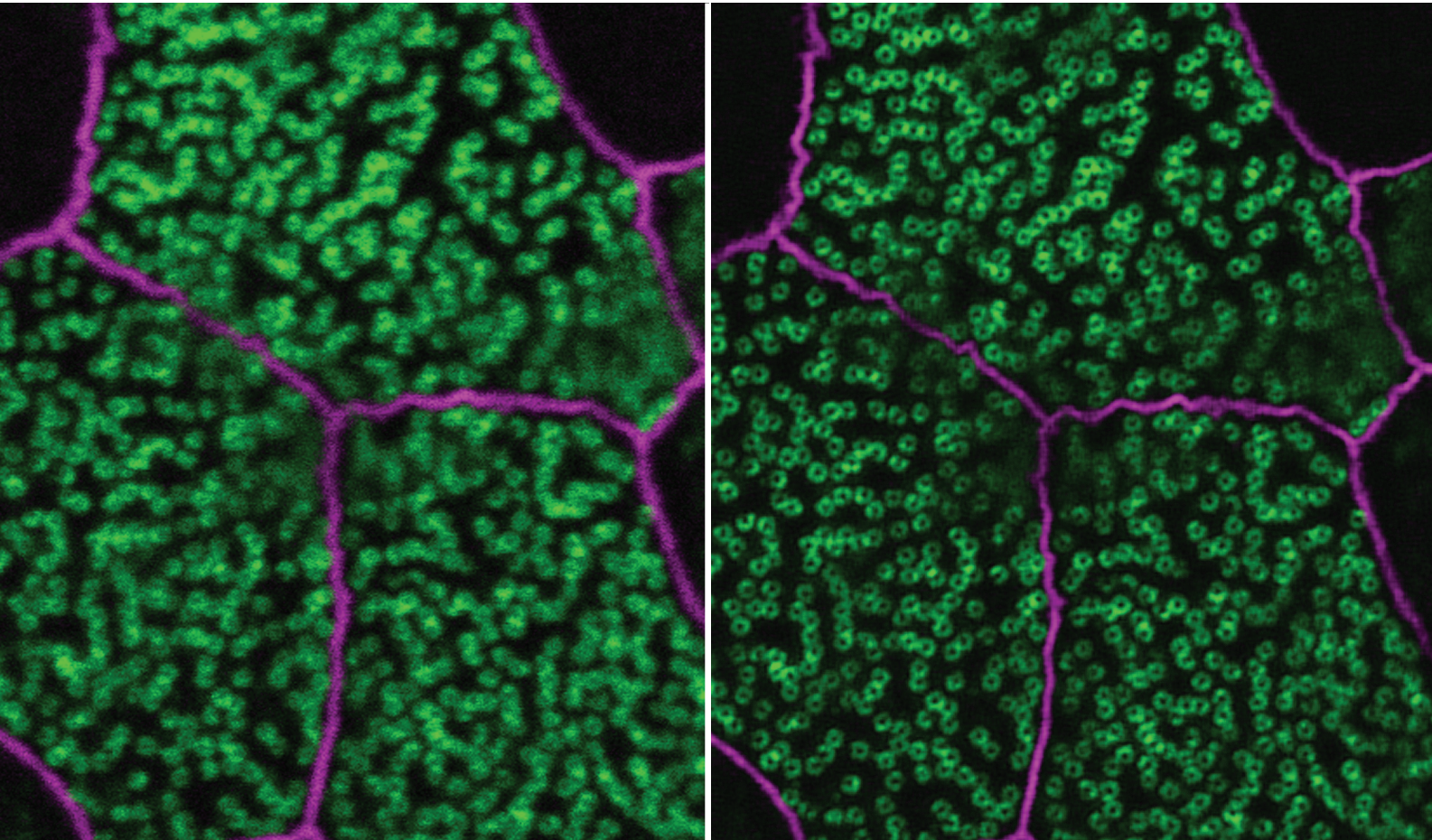


On the Cover: Platelet interaction with red blood cell. For further information please see Swanepoel and Pretorius, pp. 1848–1860.

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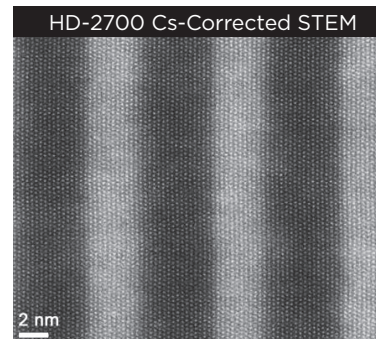
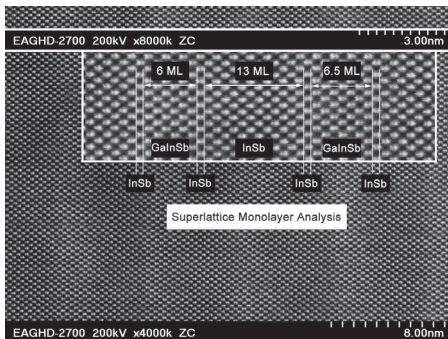
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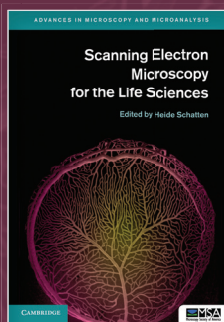
Scanning Electron Microscopy for the Life Sciences

Heide Schatten

University of Missouri, Columbia

US\$120.00: Hb: 978-0-521-19599-7: 312 pp

Recent developments in scanning electron microscopy (SEM) have resulted in a wealth of new applications for cell and molecular biology, as well as related biological disciplines. It is now possible to analyze macromolecular complexes within their three-dimensional cellular microenvironment in near native states at high resolution, and to identify specific molecules and their structural and molecular interactions. New approaches include cryo-SEM applications and environmental SEM (ESEM), staining techniques and processing applications combining embedding and resin-extraction for imaging with high resolution SEM, and advances in immuno-labeling. With chapters written by experts, this guide gives an overview of SEM and sample processing for SEM, and highlights several advances in cell and molecular biology that greatly benefited from using conventional, cryo, immuno, and high-resolution SEM.



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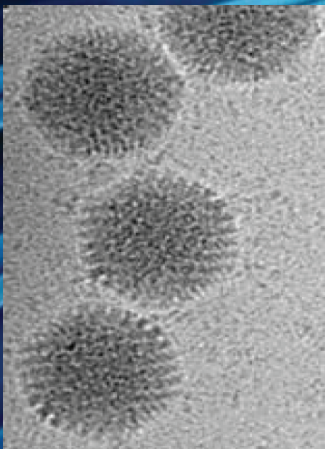
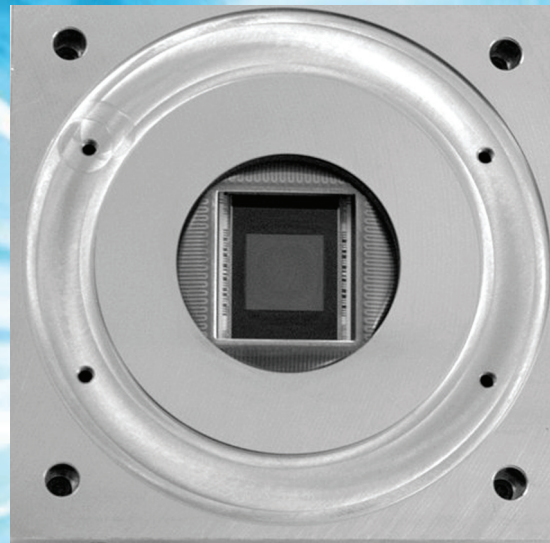


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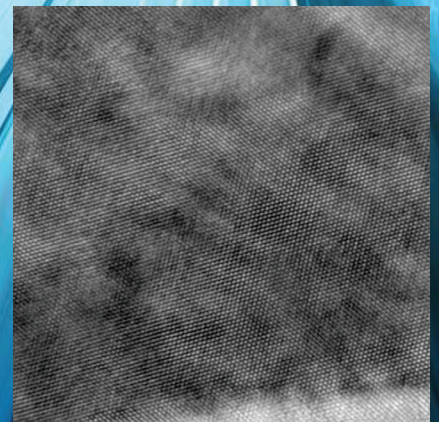
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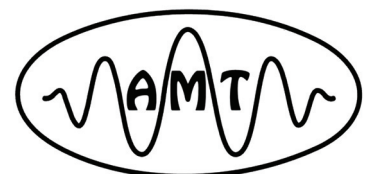
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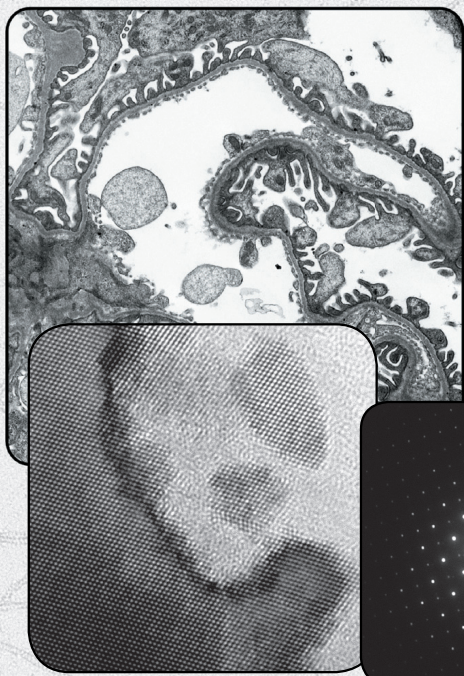
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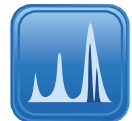
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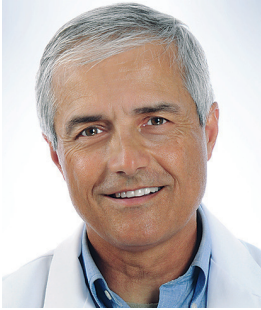
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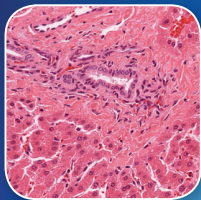
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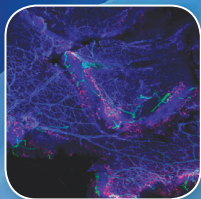
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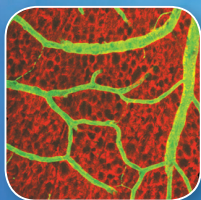


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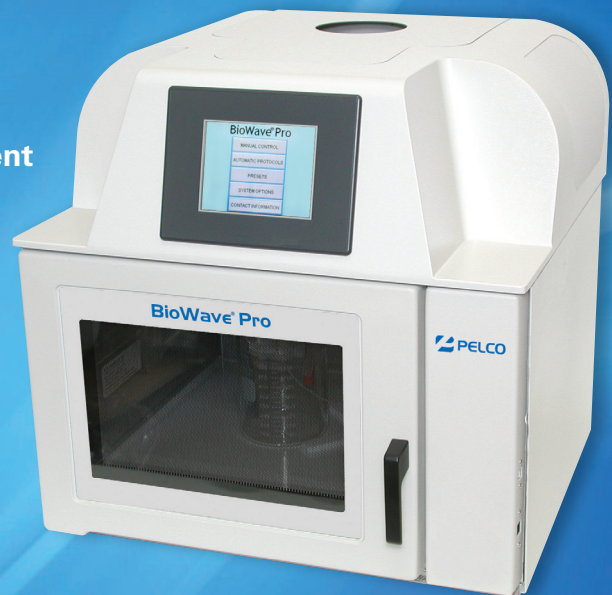
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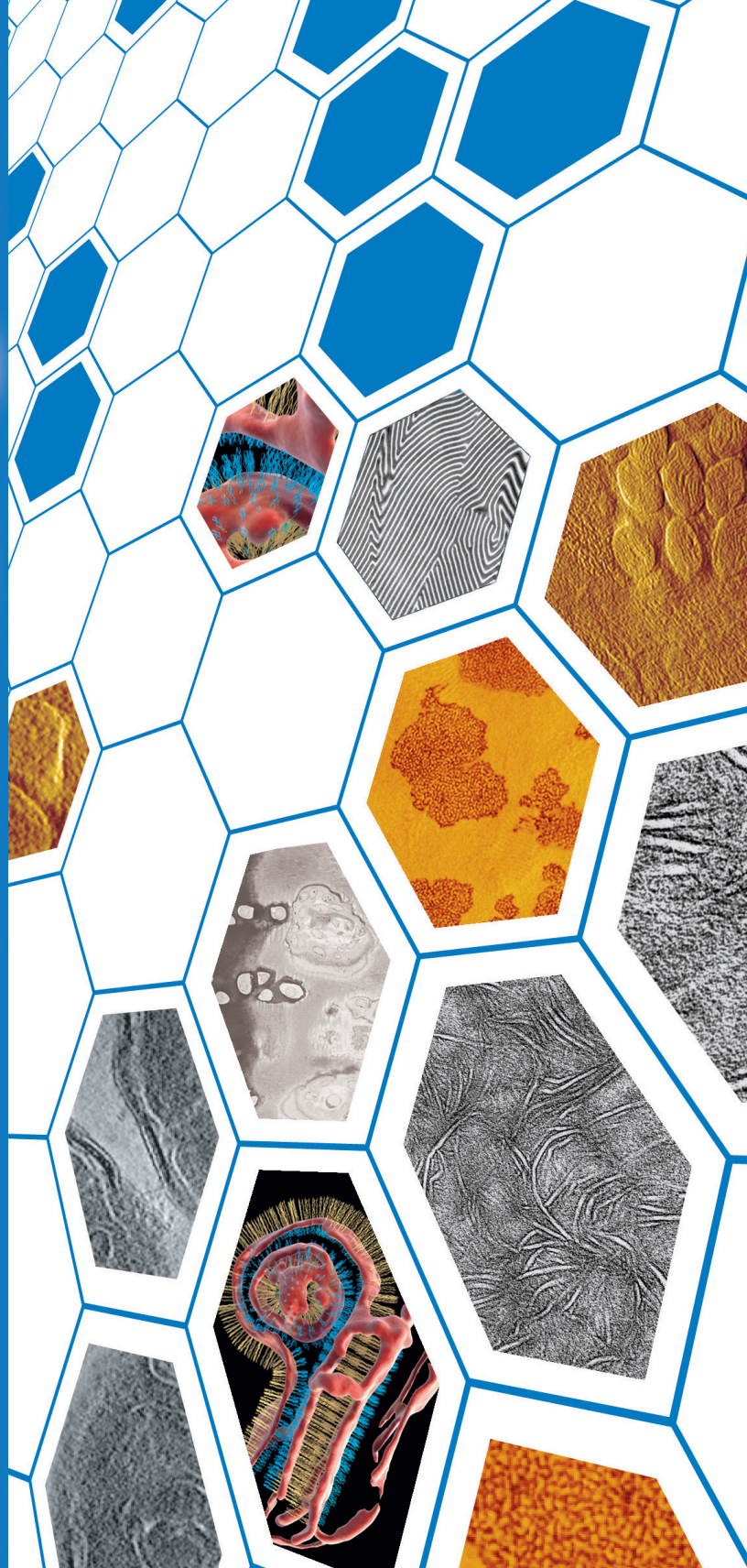
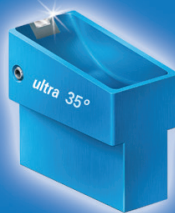
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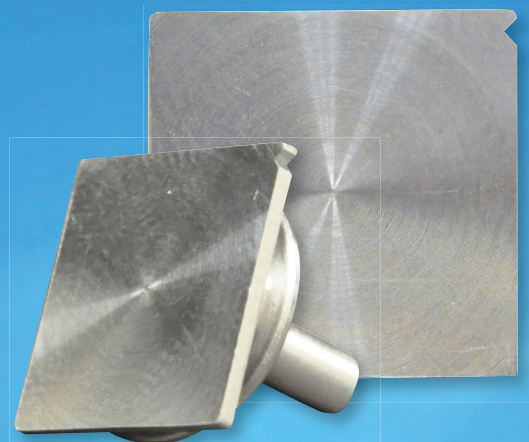
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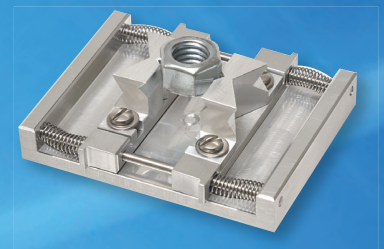
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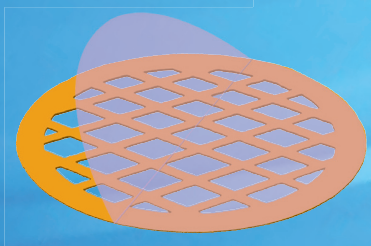
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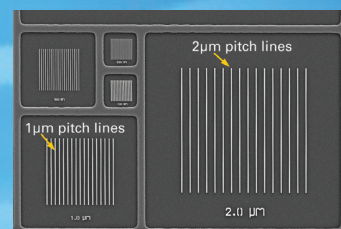
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